

<i>Notice of References Cited</i>			Application N. <b>09/745,677</b> Examiner <b>Boulosa Summons</b>		Applicant(s) <b>Karanicolas</b> Group Art Unit <b>2817</b>		Page <b>L</b> of <b>L</b>
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B	<b>5,949,295</b>	<b>9/1999</b>	<b>Schmidt</b>			<b>331</b>	<b>117R</b>
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★	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)						DATE
U	<b>Jacob Millman, Ph.D.; MICROELECTRONICS Digital and Analog Circuits and Systems</b> <b>Publishers: McGraw-Hill Books Company, New York 1979,</b> <b>page 237.</b>						
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\* A copy of this reference is not being furnished with this Office action.  
 (See Manual of Patent Examining Procedure, Section 707.05(a).)

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<b>Notice of References Cited</b>	Application/Control No. 09/745,677	Applicant(s)/Patent Under Reexamination KARANICOLAS, ANDREW N.	
	Examiner Justin P. Bettendorf	Art Unit 2817	Page 1 of 1

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	B	US-			
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	K	US-			
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	M	US-			

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.